

Notice of References Cited	Application/Control No. 10/572,505	Applicant(s)/Patent Under Reexamination SAKURAI ET AL.	
	Examiner MATTHEW D. MATZEK	Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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	N	JP 2003-082533	03-2003	Japan	Tanaka et al.	D01F 009/127
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NON-PATENT DOCUMENTS

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